

RL78/G24

Burst Dimming Control Using the Timer KB3 PWM Output Gating Function

Introduction

This application note describes how to implement burst dimming by using the RL78/G24 timers KB3 and RD2.

Target Device

RL78/G24

When applying the sample program covered in this application note to another microcomputer, modify the program according to the specifications for the target microcomputer and conduct an extensive evaluation of the modified program.

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1. Overview of Specifications

The following describes the specifications of this application note. You can implement LED burst dimming by using timers KB3 and RD2.

The PWM output gating function gates timer KB3 output by using timer RD2 output. PWM waveforms are output from the TKBO00 and TKBO01 output pins of timer KB3 only while the timer RD2 output pins (TRDIOB1 and TRDIOC1) are at High level.

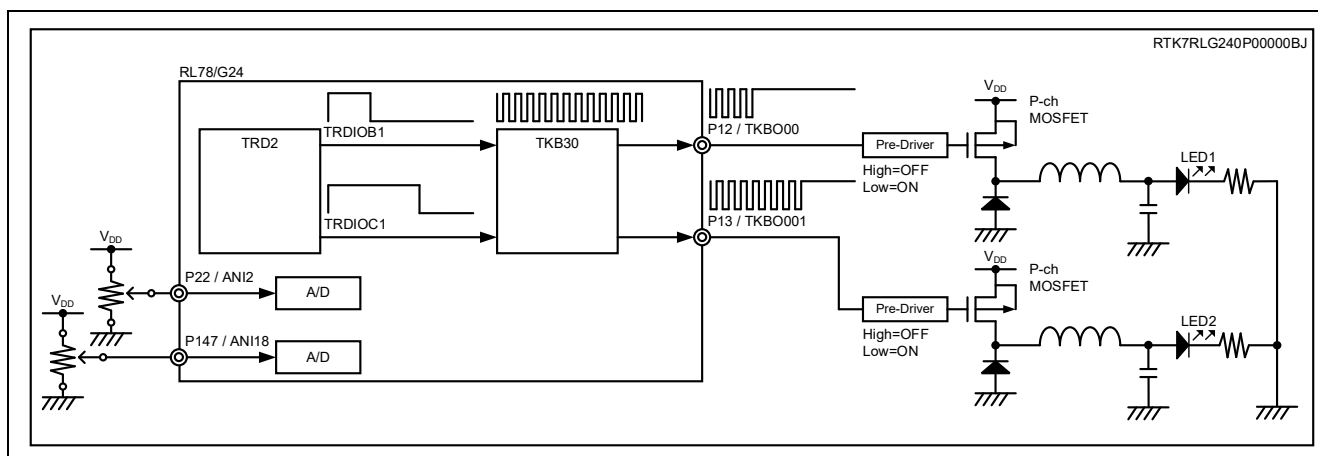
The duty ratio of timer RD2 is changed according to the input voltage to the P22/ANI2 and P147/ANI18 pins to change the PWM output period of TKBO00 and TKBO01.

Table 1-1 describes the peripheral functions and their usage. Figure 1-1 shows the system configuration for burst dimming using the PWM output gating function.

Table 1-1 Peripheral Functions and Their Usage

Peripheral Function	Usage
16-bit timer KB30 (TKB30)	PWM output from the TKBO00 pin and TKBO01 pin
Timer RD2 (TRD0, TRD1)	Controls LED lighting interlocked with timer KB3
A/D converter (Advanced mode enabled)	Performs A/D conversion of analog input voltage of the P22/ANI2 and P147/ANI18 pins

Figure 1-1 System Configuration for Burst Dimming Using PWM Output Gating Function

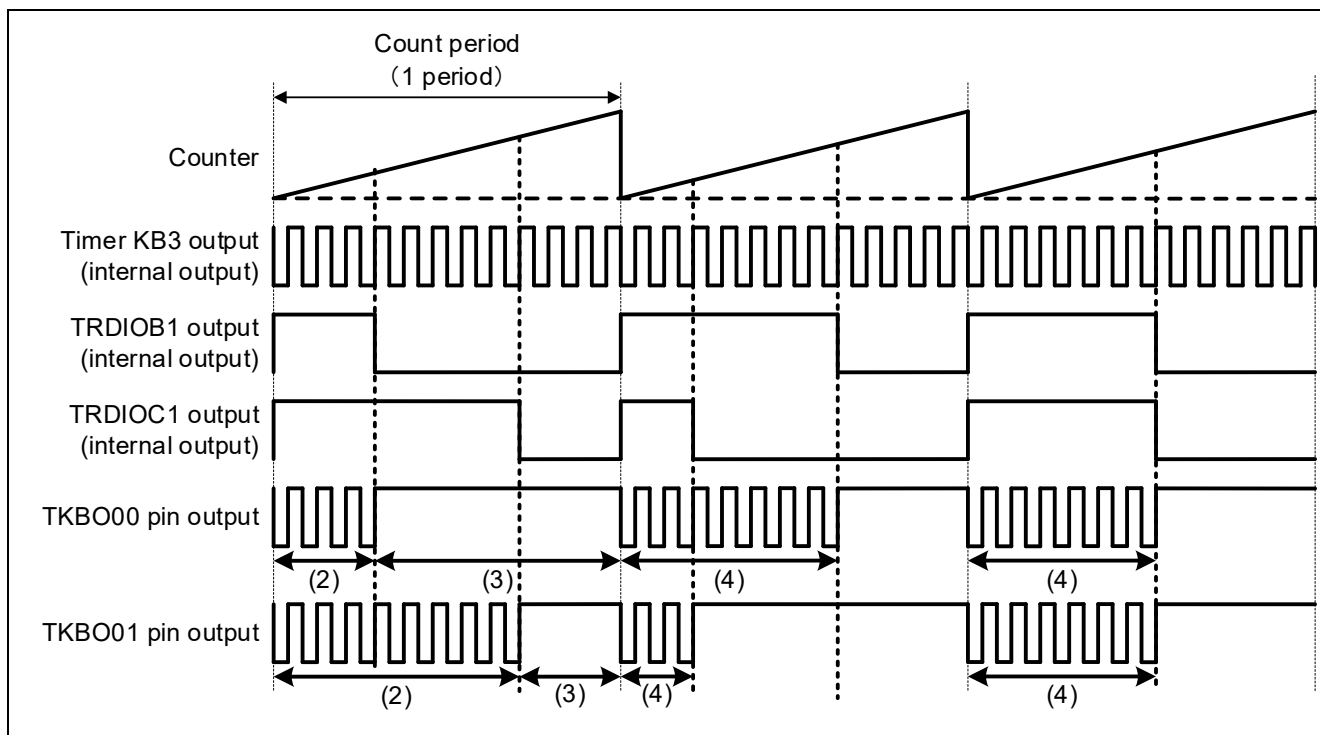


Note By using “RL78/G24 DC/DC LED DC/DC LED Control Evaluation Board”, it is possible to operate the evaluation board standalone without the need for circuit assembly. For details, please refer to “RL78 Family RTK7RLG240P00000BJ RL78/G24 DC/DC LED Control Evaluation Board User’s Manual”.

Figure 1-2 shows an example of burst dimming output using the PWM output gating function.

- (1) Timer KB3 TKBO00 and TKBO01 and timer RD2 TRDIOB1 and TRDIOC1 are set to PWM output.
- (2) The PWM output from TKBO00 is enabled while TRDIOB1 is at High level. Similarly, the PWM output from TKBO01 is enabled while TRDIOC1 is at High level.
- (3) While TRDIOB1 is at Low level, the output from TKBO00 is fixed to High (default level). Similarly, while TRDIOC1 is at Low level, the output from TKBO01 is fixed to High.
- (4) The duty ratio of TRDIOB1 and TRDIOC1 can be changed by moving the variable resistance, and the PWM output width of TKBO00 and TKBO01 to be gated can be changed respectively.

Figure 1-2 Example of Burst Dimming Output Using the PWM Output Gating Function



2. Operation Confirmation Conditions

The sample code described in this application note has been confirmed under the following conditions.

Table 2-1 Operation Confirmation Conditions

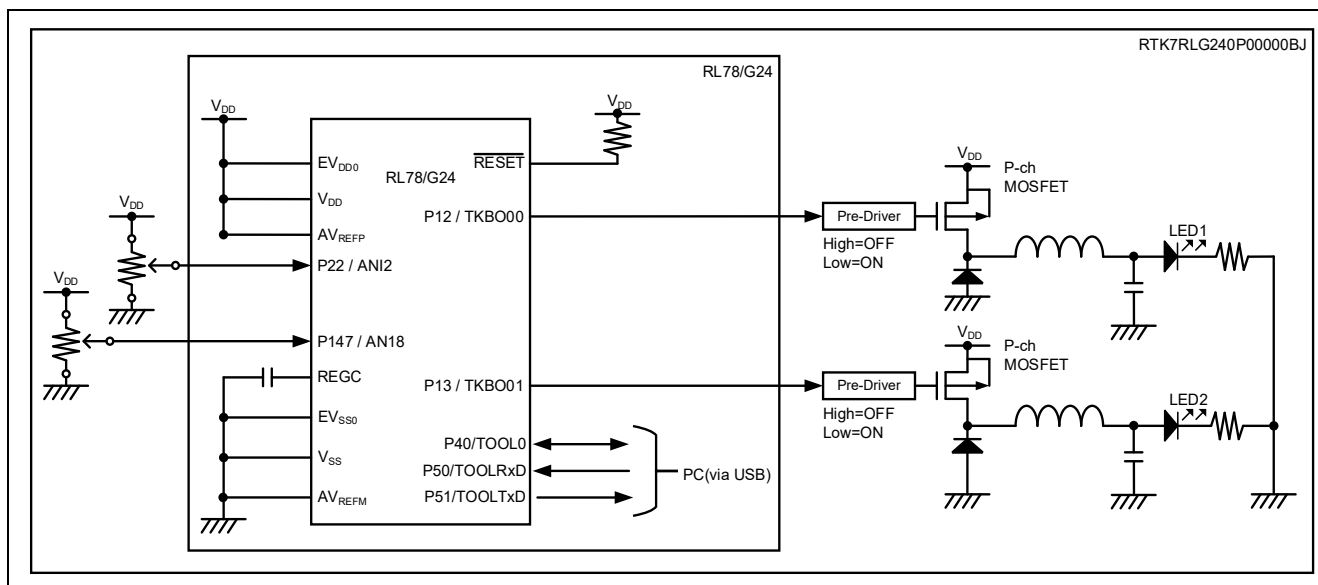
Item	Description
MCU used	RL78/G24 (R7F101GLG)
Operating frequency	- High-speed On-chip Oscillator Clock (f_{HOCO}): 8MHz - PLL Oscillator Circuit Output (f_{PLL}): 96MHz - CPU/Peripheral Hardware Clock (f_{CLK}): 48MHz
Operating voltage	3.3V (Can operate between 2.7V to 5.5V) - LVD0 Operation (V_{LVD0}): Reset Mode Rising edge TYP. 2.97V Falling edge TYP. 2.91V
Integrated development environment (CS+)	CS+ for CC V8.12.00 Manufactured by Renesas Electronics
C compiler (CS+)	CC-RL V1.14.00 Manufactured by Renesas Electronics
Integrated development environment (e ² studio)	e ² studio 2024-10 (24.10.0) Manufactured by Renesas Electronics
C compiler (e ² studio)	CC-RL V1.14.00 Manufactured by Renesas Electronics
Integrated development environment (IAR)	IAR Embedded Workbench for Renesas RL78 V5.10.3 Manufactured by IAR Systems
C compiler (IAR)	
Smart Configurator	V.1.11.0
Board Support Package (r_bsp)	V.1.70
Emulator	CS+, e ² studio: COM port IAR: E2 Emulator Lite
Board used	RL78/G24 DC/DC LED Control Evaluation Board (RTK7RLG240P00000BJ)

3. Hardware Description

3.1 Example of Hardware Configuration

Figure 3-1 shows the hardware configuration example used in the sample code for this application.

Figure 3-1 Example of Hardware Configuration



Note 1. This simplified circuit diagram was created to show an overview of connections only. When actually designing your circuit, make sure the design includes appropriate pin handling and meets electrical characteristic requirements (connect each input-only port to VDD or VSS through a resistor).

Note 2. Connect any pins whose name begins with EVSS to VSS, and any pins whose name begins with EVDD to VDD, respectively.

Note 3. VDD must not be lower than the reset release voltage (VLVD0) that is specified for the LVD0.

Note 4. It is prohibited to fix the TKBO terminal to a Low output using a general-purpose output port because the “RL78/G24 DC/DC LED Control Evaluation Board” controls the P-channel MOSFET. The LED may be damaged due to overcurrent.

3.2 List of used Pins

Table 3-1 shows the pins used and their functions.

Table 3-1 Pins Used and Their Functions

Pin Name	I/O	Function
P12 / TKBO00	Output	PWM Output (LED1 control)
P13 / TKBO01	Output	PWM Output (LED2 control)
P22 / ANI2	Input	LED1 Brightness control potentiometer
P147 / ANI18	Input	LED2 Brightness control potentiometer

Caution: In this application note, only the used pins are processed. When actually designing your circuit, make sure the design includes sufficient pin processing and meets electrical characteristic requirements.

4. Software Description

4.1 Smart Configurator Settings

The following describes the Smart Configurator settings in this sample code. The items and their descriptions in each table in the Smart Configurator settings are contained in the description of the configuration screen.

4.1.1 System settings

The following shows the system settings used in this sample code.

Note that the system settings used in this sample code are the same for integrated development environments e² studio and CS+ but are different for IAR. Specify appropriate settings according to your environment.

Figure 4-1 shows the system settings used in this sample code (e² studio or CS+).

To perform COM port debugging on the RL78/G24 Fast Prototyping Board (RTK7RLG240C00000BJ), you need to appropriately specify the settings in the integrated development environment (e² studio or CS+). For details, see **7.1 Using COM Port Debugging with the e² studio** in the **RL78/G24 Fast Prototyping Board User's Manual (R20UT5091)**.

Figure 4-1 System Configuration (e² studio, CS+)

The screenshot shows the 'System configuration' window with the following settings:

- On-chip debug setting**
 - On-chip debug operation setting: ☐ Unused, ☐ Use emulator, ☒ COM Port
 - Emulator setting: ☐ E2, ☒ E2 Lite
 - Pseudo-RRM/DMM function setting: ☐ Unused, ☒ Used
 - Start/Stop function setting: ☒ Unused, ☐ Used
 - Monitoring point function setting: ☒ Unused, ☐ Used
 - Trace function setting: ☐ Unused, ☒ Used
 - Security ID setting: ☒ Use security ID, Security ID: 0x00000000000000000000
 - Security ID authentication failure setting: ☒ Do not erase flash memory data, ☐ Erase flash memory data

Two blue boxes labeled 'Check' point to the 'COM Port' radio button and the 'Do not erase flash memory data' radio button.

Figure 4-2 shows the system configurations used in this sample program for IAR.

Figure 4-2 System Configurations (IAR)

The screenshot displays the 'System configuration' window in IAR. The 'On-chip debug setting' section is expanded, showing the following configurations:

- On-chip debug operation setting: ☒ Use emulator, ☐ COM Port
- Emulator setting: ☒ E2 Lite
- Pseudo-RRM/DMM function setting: ☒ Used
- Start/Stop function setting: ☒ Unused, ☐ Used
- Monitoring point function setting: ☒ Unused, ☐ Used
- Trace function setting: ☐ Unused, ☒ Used
- Security ID setting: ☒ Use security ID, Security ID: 0x000000000000000000000000
- Security ID authentication failure setting: ☒ Do not erase flash memory data, ☐ Erase flash memory data

Two blue boxes labeled 'Check' are present. The first 'Check' box has two arrows pointing to the 'E2 Lite' and 'Used' radio buttons. The second 'Check' box has an arrow pointing to the 'Do not erase flash memory data' radio button.

4.1.2 Component Configurations

This section presents the component configurations used in this sample code.

Table 4-1 Component Configurations (Timer KB3)

Item	Content
Component	PWM output
Configuration Name	Config_TKB0
Resource	TKB0
Operation	Standalone mode (period controlled by the TKBCRn0 register)

Figure 4-3 Configuration of Timer KB3

The screenshot shows the configuration interface for Timer KB3. The following settings are highlighted with blue boxes and callouts:

- Count source setting:**
 - Operation clock: CK20
 - Clock source: fKBKC (Clock frequency: 96000 kHz, fPLL is selected as fKBKC)
- PWM output setting:**
 - PWM period: 2 μ s (Actual value: 2)
 - Duty (TKBO00 output): 50 (%) (Actual value: 50)
 - Duty (TKBO01 output): 70 (%) (Actual value: 69.792)
 - Delay (TKBO01 output): 0 (%) (Actual value: 0)
- A/D conversion start timing signal output function setting:**
 - TKBTGCR0 value: 100
- Output setting:**
 - ☒ Enable TKBO00 output
 - Default level: High level (Callout: "Change to 'High level'")
 - Active level: Low level (Callout: "Change to 'High level'")
 - ☒ Enable TKBO01 output
 - Default level: High level (Callout: "Change to 'High level'")
 - Active level: Low level (Callout: "Change to 'High level'")
- PWM output gating function setting:**
 - Enable TKBO00 output gating function: Enable (Callout: "Change to 'Enable'")
 - Enable TKBO01 output gating function: Enable (Callout: "Change to 'Enable'")
- Interrupt setting:**
 - ☐ Generate interrupt when TKBO00 forced stopping of the output is terminated
 - Priority: Level 3 (low)
 - ☐ Generate interrupt when TKBO00 forced stopping of the output is activated
 - Priority: Level 3 (low)
 - ☐ Generate interrupt when TKBO01 forced stopping of the output is terminated
 - Priority: Level 3 (low)
 - ☐ Generate interrupt when TKBO01 forced stopping of the output is activated
 - Priority: Level 3 (low)
 - ☐ Enable 16-bit timer KB30 end count (Callout: "Uncheck")
 - Priority: Level 3 (low)

Note. The LED2 (green), controlled by the TKBO01 output, has a higher forward voltage (VF) than LED1 (red), which is controlled by the TKBO00 output. Therefore, the duty cycle is set to "70%" to increase the voltage applied to the LED by setting a higher duty cycle.

Table 4-2 Component Configurations (Timer RD2)

Item	Content
Component	PWM output
Configuration Name	Config_TRD0_TRD1
Resource	TRD0_TRD1
Operation	Timer KB3 PWM output gating mode

Figure 4-4 Configuration of Timer RD2

Configure

Count source setting

Operation clock: CK20

Clock source: fKBKC (Clock frequency: 96000 kHz, fPLL is selected as fKBKC)

Operation setting

Operation mode: **Change to "Timer KB3 interlocked mode"** Timer KB3 interlocked mode

Output period setting: Two and four PWM waveforms with two different periods

Counter setting

TRD0 counter operation: Count continues after TRDGRA0 compare match

TRD1 counter operation: Count continues after TRDGRA1 compare match

PWM output setting

Two or six PWM period: 100 μ s (Actual value: 100)

☐ Enable TRDIOB0/TRDTKBOUT4 output **Uncheck**

☐ Enable TRDIOD0/TRDTKBOUT5 output **Change to "50"** 50 μ s (Actual value: 50)

Four PWM period

☒ Enable TRDIOB1/TRDTKBOUT0 output **Change to "TRDIOB1 and TRDTKBOUT0"** 50 μ s (Actual value: 50) **Change to "'H' active"** "H" active

☒ Enable TRDIOC1/TRDTKBOUT1 output **Change to "TRDIOC1 and TRDTKBOUT"** 50 μ s (Actual value: 50) **Change to "'H' active"** "H" active

☐ Enable TRDIOD1/TRDTKBOUT2 output **Uncheck**

☐ Enable TRDIOA1/TRDTKBOUT3 output **Change to "TRDIOC1 and TRDTKBOUT"** 50 μ s (Actual value: 50) **Change to "'H' active"** "H" active

Pulse output forced cutoff setting

☐ Enable forced cutoff by INTP0 low-level input
If INTP0 cutoff is selected, please do not select INTP0 in PWMOPA function.

☐ Enable forced cutoff by ELC event input
If ELC cutoff is selected, please do not select ELC in PWMOPA function.

TRDIOB0 pin output: Forced cutoff disabled

TRDIOA1 pin output: Forced cutoff disabled

TRDIOC1 pin output: Forced cutoff disabled

TRDIOD0 pin output: Forced cutoff disabled

TRDIOB1 pin output: Forced cutoff disabled

TRDIOD1 pin output: Forced cutoff disabled

Interrupt setting

☐ Enable TRDGRA0 compare match interrupt **Uncheck** ☐ Enable TRDGRA1 compare match interrupt

INTTRD0 priority: Level 3 (low)

INTTRD1 priority: Level 3 (low)

Table 4-3 Component Configurations (A/D Converter)

Item	Content
Component	A/D Converter
Configuration Name	Config_ADC
Resource	ADC
Operation Mode	Advanced mode

Figure 4-5 Configuration of A/D Converter (1/2)

Configure

Comparator operation setting

☒ Stop ☐ Operation

Resolution setting

☐ 10 bits ☐ 8 bits ☒ 12 bits

Check

VREF(+) setting

☐ VDD ☒ AVREFP ☐ Internal reference voltage

Check

VREF(-) setting

☐ VSS ☒ AVREFM

Check

Simultaneous sampling setting

Simultaneous sampling: Unused

Trigger source: INTTM01 signal

First S&H circuit input source: ANI0

Second S&H circuit input source: ANI2

Third S&H circuit input source: ANI3

Conversion priority: Low

Operation mode setting

One-shot select mode

A/D channel 0 setting

☒ Enable A/D channel 0 (ADS0)

Check

Trigger source: Software trigger

Input source: ANI2

Conversion priority: Low

Change to "Software trigger"

Change to "ANI2"

A/D channel 1 setting

☒ Enable A/D channel 1 (ADS1)

Check

Trigger source: Software trigger

Input source: ANI18

Conversion priority: Low

Change to "Software trigger"

Change to "ANI18"

Figure 4-6 Configuration of A/D Converter (2/2)

A/D channel 2 setting	
☐ Enable A/D channel 2 (ADS2)	
Trigger source	ELCITL0 signal
Input source	ANI2
Conversion priority	Low
A/D channel 3 setting	
☐ Enable A/D channel 3 (ADS3)	
Trigger source	Event input from ELC
Input source	ANI3
Conversion priority	Low
Conversion time setting	
Please set fCLK not greater than 48MHz	
Conversion time mode	Normal 1
Sampling clock cycles	27 fAD
Conversion time	50/fCLK (1.0417 μs)
Conversion result upper/lower bound value setting	
☒ Generates an interrupt request (INTAD0 to INTAD3) when $ADLL \leq ADCRn \leq ADUL$ ☐ Generates an interrupt request (INTAD0 to INTAD3) when $ADUL < ADCRn$ or $ADLL > ADCRn$	
Upper bound (ADUL) value	255
Lower bound (ADLL) value	0
Interrupt setting	
☒ Use A/D channel 0 interrupt (INTAD0)	Priority: Level 3 (low)
☐ Enable storage of the conversion state information for the analog input channel specified by ADS0 in response to failure	
☒ Use A/D channel 1 interrupt (INTAD1)	Priority: Level 3 (low)
☐ Enable storage of the conversion state information for the analog input channel specified by ADS1 in response to failure	
☐ Use A/D channel 2 interrupt (INTAD2)	Priority: Level 3 (low)
☐ Enable storage of the conversion state information for the analog input channel specified by ADS2 in response to failure	
☐ Use A/D channel 3 interrupt (INTAD3)	Priority: Level 3 (low)
☐ Enable storage of the conversion state information for the analog input channel specified by ADS3 in response to failure	

4.2 Folder Structure

Table 4-4 shows the structure of the source files/header files used in the sample code. Note that files automatically generated by the integrated development environment and files from the BSP environment are excluded.

Table 4-4 Folder Structure

Folder/File Name	Description	Generated by Smart Configurator
\r01an7256_tkb3_trd2_dimming<DIR> ^{NOTE 2}	Sample code folder	
\src<DIR>	Program storage folder	
main.c	Sample code source file	
\smc_gen<DIR>	Smart configurator generated folder	√
\Config_ADC<DIR>	ADC program storage folder	√
Config_ADC.c	ADC source file	√
Config_ADC.h	ADC header file	√
Config_ADC_user.c	ADC interrupt source file	√
\Config_TKB0<DIR>	TKB0 program storage folder	√
Config_TKB0.c	TKB0 source file	√
Config_TKB0.h	TKB0 header file	√
Config_TKB0_user.c	TKB0 interrupt source file	√ ^{NOTE 1}
\Config_TRD0_TRD1<DIR>	TRD0_TRD1 program storage folder	√
Config_TRD0_TRD1.c	TRD0_TRD1 source file	√
Config_TRD0_TRD1.h	TRD0_TRD1 header file	√
Config_TRD0_TRD1_user.c	TRD0_TRD1 interrupt source file	√ ^{NOTE 1}
¥general<DIR>	Initialization and common program storage folder	
¥r_bsp<DIR>	BSP program storage folder	
¥r_config<DIR>	Program storage folder	

Note: "<DIR>" indicates a directory.

Note 1. This sample code does not use it.

Note 2. The sample code for IAR contains the r01an6893_trd2_pwm.ipcf file.

For details on the .ipcf file, please refer to "RL78 Smart Configurator User's Guide: IAR" (R20AN0581).

4.3 List of Option Byte Settings

Table 4-5 shows the option byte settings.

Table 4-5 Option Byte Settings

Address	Setting Value	Description
000C0H/040C0H	1110 1111B (EFH)	Watchdog Timer stopped operation (Count stops after reset release)
000C1H/040C1H	1111 1011B (FBH)	LVD0 reset mode Detection voltage: Rising 2.97V / Falling 2.91V
000C2H/040C2H	1110 1010B (EAH)	Flash operation mode: High-speed main mode. High-speed on-chip oscillator frequency: 8MHz
000C3H/040C3H	1000 0101B (85H)	On-chip debug operation allowed

4.4 List of Constants

Constant is not used in the sample code.

4.5 List of Variables

Table 4-6 shows the variables used in the sample code.

Table 4-6 Variables Used in the Sample Code

Variable Name	Type	Content	Function that uses the variables
g_result_buffer0	uint16_t	Channel 0 A/D conversion result storage	r_Config_ADC_ad0_interrupt
g_result_buffer1	uint16_t	Channel 1 A/D conversion result storage	r_Config_ADC_ad1_interrupt
g_duty_result0	uint16_t	Channel 0 duty ratio calculation result storage	r_Config_ADC_ad0_interrupt
g_duty_result1	uint16_t	Channel 1 duty ratio calculation result storage	r_Config_ADC_ad1_interrupt

4.6 List of Functions

Table 4-7 lists the functions used in the sample code. However, functions generated by the Smart Configurator that have not been modified are excluded.

Table 4-7 List of Functions

Function Name	Description	Source File
main	Main process	main.c
r_Config_ADC_ad0_interrupt	A/D converter channel 0 interrupt process	Config_ADC_user.c
r_Config_ADC_ad1_interrupt	A/D converter channel 1 interrupt process	Config_ADC_user.c

4.7 Function Specifications

The following describes the function specifications of the sample code.

[Function name] main

Overview	Main processing
Headers	r_smc_entry.h
Declaration	void main (void);
Description	This function specifies the initial settings of the A/D converter, comparator, D/A converter, and TKB30, and generates software triggers.
Arguments	None
Return values	None
Remarks	None

[Function name] r_Config_ADC_ad0_interrupt

Overview	A/D converter channel 0 interrupt processing
Headers	r_cg_macrodriver.h, r_cg_userdefine.h, Config_ADC.h
Declaration	static void __near r_Config_ADC_ad0_interrupt(void);
Description	This function reads the A/D conversion result from the ADCR0 register and then stores the result in the variable of the internal RAM. This function calculates the duty ratio based on the stored conversion results, and then changes the duty ratio of TKB30.
Arguments	None
Return values	None
Remarks	None

[Function name] r_Config_ADC_ad1_interrupt

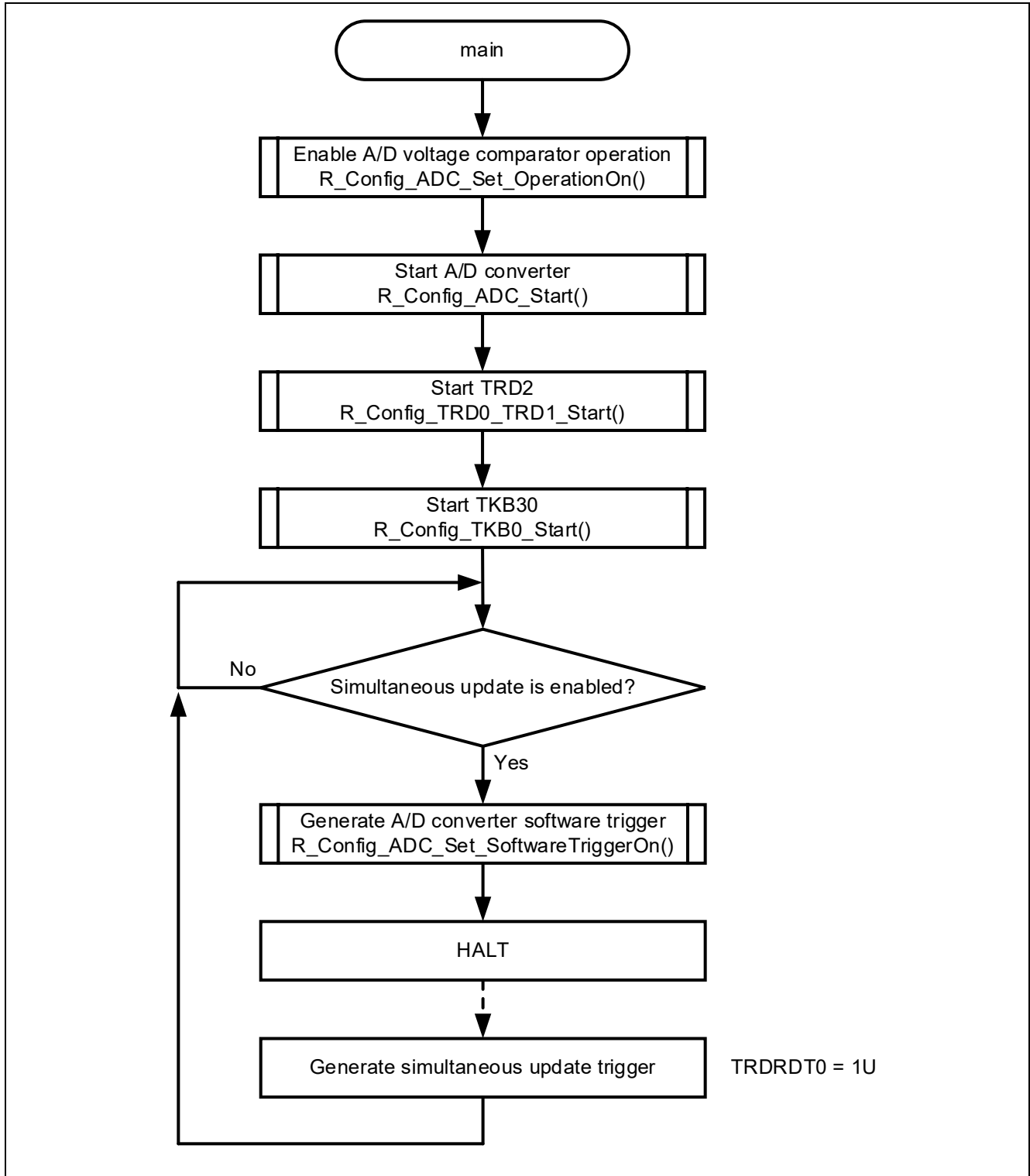
Overview	A/D converter channel 1 interrupt processing
Headers	r_cg_macrodriver.h, r_cg_userdefine.h, Config_ADC.h
Declaration	static void __near r_Config_TKB0_activated1_interrupt(void);
Description	This function reads the A/D conversion result from the ADCR0 register and then stores the result in the variable of the internal RAM. This function calculates the duty ratio based on the stored conversion results, and then changes the duty ratio of TKB30.
Arguments	None
Return values	None
Remarks	None

4.8 Flowchart

4.8.1 Main Process

Figure 4-7 shows the flowchart for the main process.

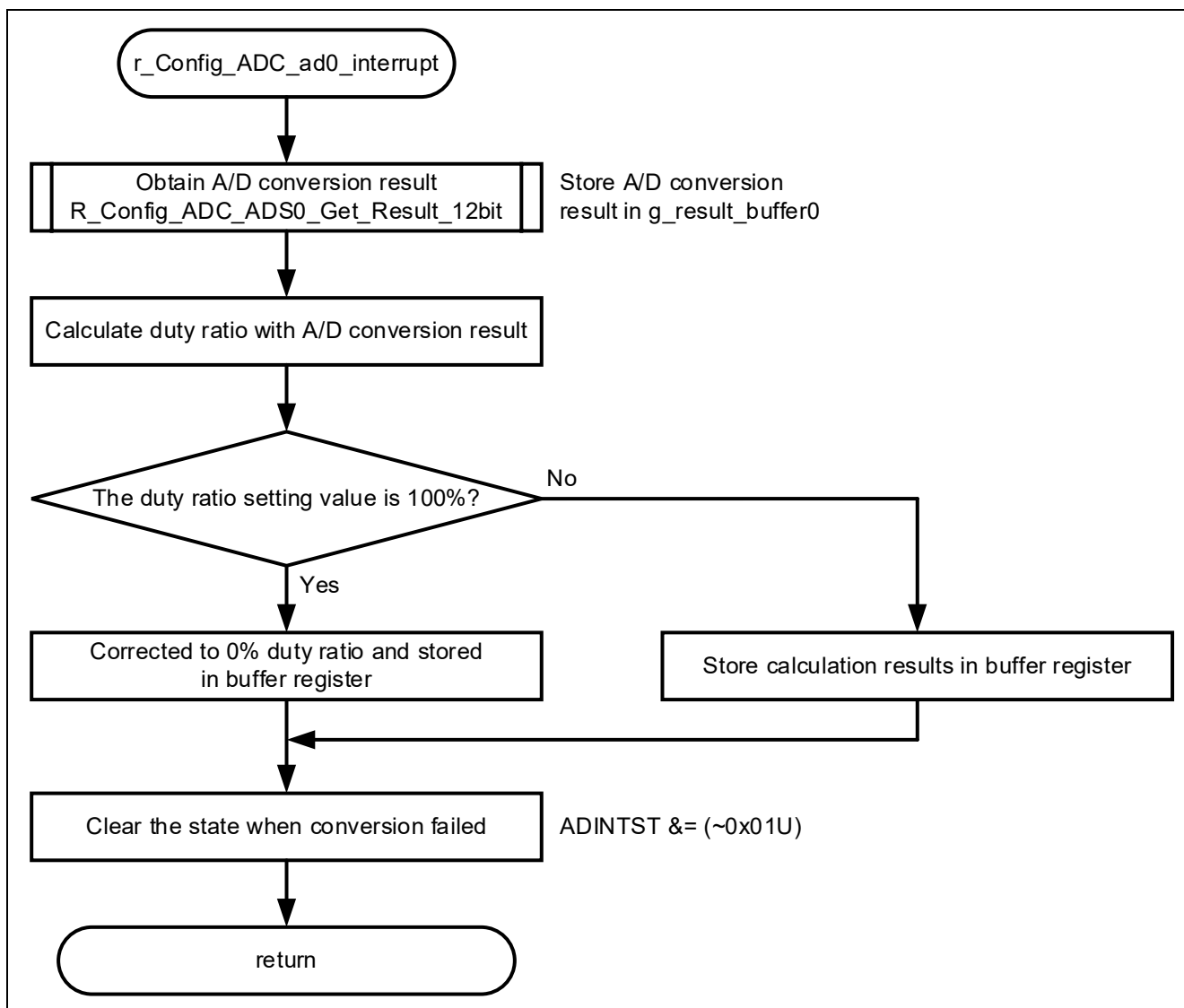
Figure 4-7 Main Process



4.8.2 r_Config_ADC_ad0_interrupt function

Figure 4-8 shows the flowchart of r_Config_ADC_ad0_interrupt function.

Figure 4-8 r_Config_ADC_ad0_interrupt function

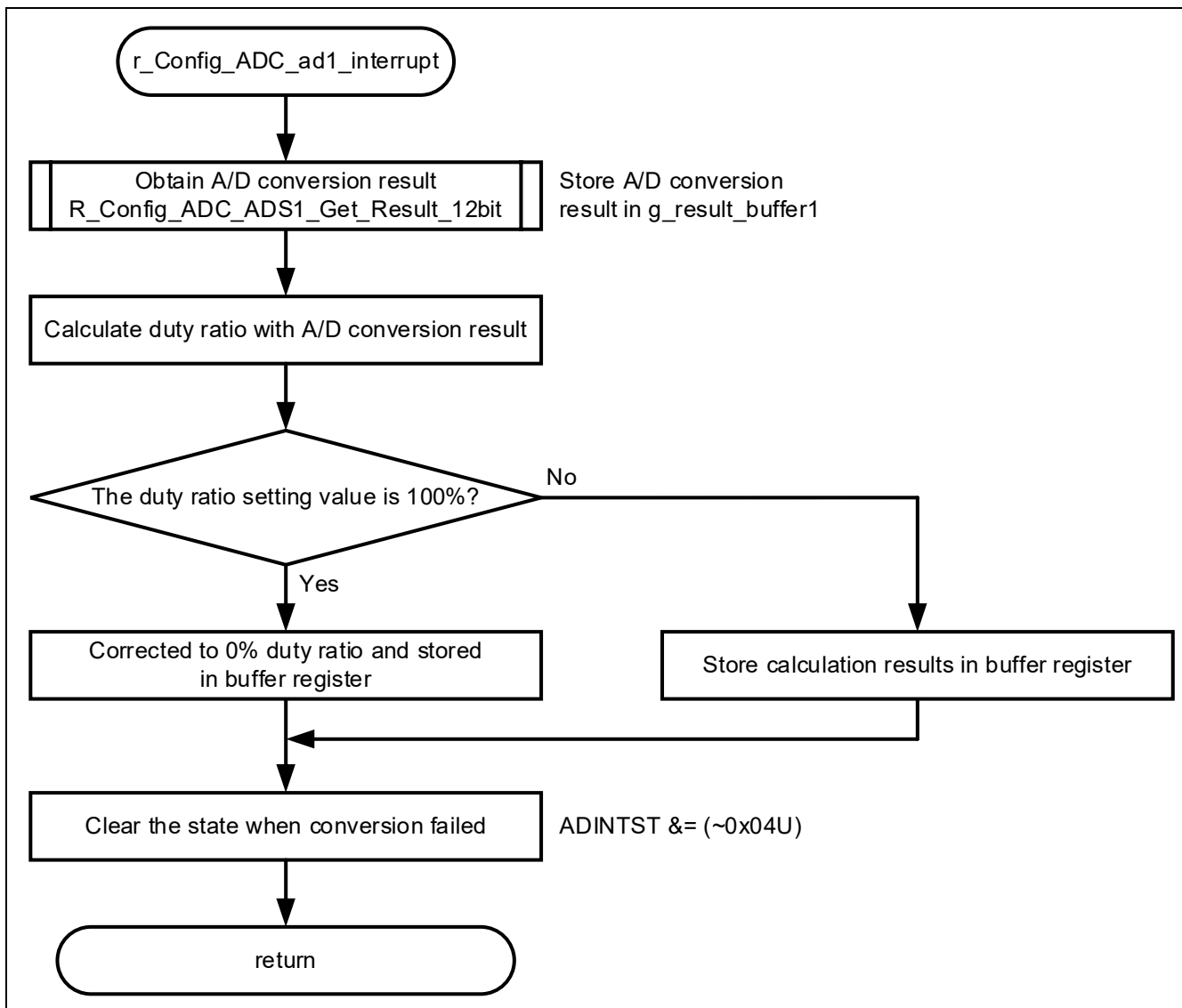


Note. In the Timer KB PWM output gate mode, a simultaneous rewrite process is required to activate the value set in the compare register. Since there is a specific procedure for setting the related registers for the simultaneous rewrite, please refer to “RL78/G24 User’s Manual: Hardware,” section “12.4.7 Simultaneous update of compare registers” for detailed instructions.

4.8.3 r_Config_ADC_ad1_interrupt function

Figure 4-9 shows the flowchart of r_Config_ADC_ad1_interrupt function.

Figure 4-9 r_Config_ADC_ad1_interrupt function.



5. Sample Code

Sample code can be downloaded from the Renesas Electronics website.

6. Reference Documents

RL78/G24 User's Manual: Hardware (R01UH0961)

RL78 family User's Manual: Software (R01US0015)

RL78/G24 Fast Prototyping Board User's Manual (R20UT5091)

RL78 Smart Configurator User's Guide: CS+ (R20AN0580)

RL78 Smart Configurator User's Guide: e2 studio (R20AN0579)

RL78 Smart Configurator User's Guide: IAR (R20AN0581)

RL78 family RTK7RLG240P00000BJ RL78/G24 DC/DC LED Control Evaluation Board
User's Manual (R20UT5371)

(The latest version can be downloaded from the Renesas Electronics website.)

Technical Update/Technical News

(The latest version can be downloaded from the Renesas Electronics website.)

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Revision History

Rev.	Date	Description	
		Page	Summary
1.00	Dec.10.24	—	First Edition

General Precautions in the Handling of Microprocessing Unit and Microcontroller Unit Products

The following usage notes are applicable to all Microprocessing unit and Microcontroller unit products from Renesas. For detailed usage notes on the products covered by this document, refer to the relevant sections of the document as well as any technical updates that have been issued for the products.

1. Precaution against Electrostatic Discharge (ESD)

A strong electrical field, when exposed to a CMOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop the generation of static electricity as much as possible, and quickly dissipate it when it occurs. Environmental control must be adequate. When it is dry, a humidifier should be used. This is recommended to avoid using insulators that can easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.

2. Processing at power-on

The state of the product is undefined at the time when power is supplied. The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the time when power is supplied. In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the time when power is supplied until the reset process is completed. In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the time when power is supplied until the power reaches the level at which resetting is specified.

3. Input of signal during power-off state

Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.

4. Handling of unused pins

Handle unused pins in accordance with the directions given under handling of unused pins in the manual. The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of the LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible.

5. Clock signals

After applying a reset, only release the reset line after the operating clock signal becomes stable. When switching the clock signal during program execution, wait until the target clock signal is stabilized. When the clock signal is generated with an external resonator or from an external oscillator during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Additionally, when switching to a clock signal produced with an external resonator or by an external oscillator while program execution is in progress, wait until the target clock signal is stable.

6. Voltage application waveform at input pin

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (Max.) and V_{IH} (Min.) due to noise, for example, the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (Max.) and V_{IH} (Min.).

7. Prohibition of access to reserved addresses

Access to reserved addresses is prohibited. The reserved addresses are provided for possible future expansion of functions. Do not access these addresses as the correct operation of the LSI is not guaranteed.

8. Differences between products

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